

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.	10/539,247	Conf. No.	9258
In Re Application of:	Gattiker <i>et al.</i>	Art Unit:	2829
Filed:	06/16/2005	Dkt. #:	BUR920020068US1 (IBMF-0010)
		Examiner:	Nguyen, Vinh P.

Title: **INTEGRATED CIRCUIT TESTING METHODS USING WELL BIAS MODIFICATION**

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT**

Sir:

**I. INTRODUCTORY COMMENTS**

In response to the Office Action of June 11, 2007, please reconsider the above-referenced patent application in light of the following remarks:

**The Claims** are reflected in the listing of claims that begin on page 2 of this paper.

**Remarks** begin on page 9 of this paper.